

INPADOC

(INternational PATent DOCumentation DataBase)

Subject Coverage	<ul style="list-style-type: none"> All areas of science and technology, i.e., all classes of the International Patent Classification 																
File Type	Bibliographic																
Features	<table border="0"> <tr> <td>Thesaurus</td> <td>International Patent Classification (/IPC)</td> </tr> <tr> <td>Alerts (SDIs)</td> <td>Weekly or monthly (Weekly is the default)</td> </tr> <tr> <td>CAS Registry Numbers®</td> <td><input type="checkbox"/> Page Images <input type="checkbox"/></td> </tr> <tr> <td>Keep & Share</td> <td><input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/></td> </tr> <tr> <td>Learning Database</td> <td><input checked="" type="checkbox"/> Structures <input type="checkbox"/></td> </tr> <tr> <td></td> <td>STN AnaVist <input type="checkbox"/></td> </tr> <tr> <td></td> <td>STN Easy <input checked="" type="checkbox"/></td> </tr> <tr> <td></td> <td>STN Viewer <input type="checkbox"/></td> </tr> </table>	Thesaurus	International Patent Classification (/IPC)	Alerts (SDIs)	Weekly or monthly (Weekly is the default)	CAS Registry Numbers®	<input type="checkbox"/> Page Images <input type="checkbox"/>	Keep & Share	<input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/>	Learning Database	<input checked="" type="checkbox"/> Structures <input type="checkbox"/>		STN AnaVist <input type="checkbox"/>		STN Easy <input checked="" type="checkbox"/>		STN Viewer <input type="checkbox"/>
Thesaurus	International Patent Classification (/IPC)																
Alerts (SDIs)	Weekly or monthly (Weekly is the default)																
CAS Registry Numbers®	<input type="checkbox"/> Page Images <input type="checkbox"/>																
Keep & Share	<input checked="" type="checkbox"/> SLART <input checked="" type="checkbox"/>																
Learning Database	<input checked="" type="checkbox"/> Structures <input type="checkbox"/>																
	STN AnaVist <input type="checkbox"/>																
	STN Easy <input checked="" type="checkbox"/>																
	STN Viewer <input type="checkbox"/>																
Record Content	<ul style="list-style-type: none"> Bibliographic and family data of patent documents and utility models of more than 90 patent-issuing organizations including the European Patent Office (EPO) and the World Intellectual Property Organization (WIPO) Legal status data of 58 patent-issuing organizations (42 countries + from 16 countries of the national phases PCT/EP) Over 25.7 million abstracts are available Note: The accession number can change due to corrections/updates of patent relevant numbers and codes 																
File Size	<p>More than 55 million records (applications) including national patent families with about 70 million publications; 36 million families (01/10) from 1790 to the present</p> <p>More than 52 million legal status data in almost 20 million records (01/10) from 1978 to the present</p> <p>More than 83 million patent and non-patent citations are available for 21 authorities from 1978 to the present</p>																
Coverage	1790-present																
Updates	Weekly with 70,000-1.000,000 records and 40,000-180,000 legal status data																
Language	English																
Database Producer	<p>European Patent Office Vienna Sub Office P.O. Box 90 Austria Phone: +43 1 52126-0 Fax: +43 1 52126-5491 E-mail: inpadoc.help@epo.org Copyright Holder</p>																

Database Supplier FIZ Karlsruhe
STN Europe
P.O. Box 2465
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Germany
Phone: +49 7247 808-555
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 - INPADOC Legal Status Service
-

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
 - ECLA (EPC, ICO) and IDT descriptions in pdf files – updated monthly (see file banner)
 - More information and additional links see on the INPADOCDB/INPAFAMDB web site
http://www.stn-international.de/details_inpadocdb.html
http://www.stn-international.de/inpadocdb_inpafamdb_handbook.html
-

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Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

Bibliographic Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI) and abstract (AB) fields)	None or /BI	S TUBULAR HEAT EXCHANG? S ALUM? (S) COAT? S ?MAGNET? S ?METHYL?(T)?AMINO?	AB, ABDE, ABFR, ABES, ABOL, TI
Abstract (contains AB, ABDE, ABES, ABFR, ABOL) (1)	/AB	S (DRILLING(W)PROCESS)/AB	AB, ABDE, ABES, ABFR, ABOL AI
Application Country (WIPO code and text)	/AC	S WO/AC AND (INLAND(W)STEEL)/PA	AI
Filing Country for PCT Application	/AC.WO	S FR/AC.WO	AI
Application Date (2)	/AD	S 19840705/AD	AI
Application Kind Code Text	/AIT	S MWA/AIT	AIT
Application Kind Code	/AK	S WOW/AK	AI, AIT
Abstract Language (ISO code and text)	/AL	S DUTCH/AL	ALL, ALLO, IMAX, MAX, MAXO AN
Accession Number	/AN	S 12345678/AN	AN
Application Number (4)	/AP	S ZW1981-215/AP	AI
Application Year (2)	/AY	S 1988/AY AND SIEMENS/PAS	AI
Citation Category	/CAT	S X/CAT	REN, REP
Changes (Indicator for the changes in the last update)	/CHG	S EPC C/CHG	CHG
Data Availability	/DAV	S NOT-PRINTED-WITH-GRANT/DAV	DAV
Data Force (2,4)	/DF	S 20070401/DF	DF
Designated States	/DS	S W JP/DS	DS
Document Type (code and text)	/DT (or /TC)	S U/DT AND UNILEVER/PAS	DT
Entry Date (2,5)	/ED	S L1 AND ED>1 JAN 2007	ED
Entry Date New Patent Family (2)	/EDF	S 20070321/EDF	EDF
Entry Date new publication and/or New Legal Status (2)	/EDLS	S EDLS=20070419	not displayed
Entry Date Patent (2,5)	/EDP	S 20061130/EDP	EDP
Entry Date Priority (2,5)	/EDPR	S 20070401-20070429/EDPR	PRAI
European Patent Classification	/EPC	S A01B0015-20/EPC	EPC
EPC, Keyword Terms	/EPC.KW	S D2/EPC.KW	EPC
Entry Week (INPADOC) (2,6)	/EW	S 200801/EW	EW
Field Availability	/FA	S L7 AND DS/FA	FA
Filing Details	/FDT	S DEC3D6/FDT	FDT
IPC (contains ICM and ICS), Version 1-7 (7)	/IC	S C07H019-16/IC	IC
IPC, Version from IC	/IC.VER	S 7/IC.VER AND L5	IC.VER, IC
IPC, Additional (supplementary) Version 1-7 (7)	/ICA	S A61K037-64/ICA	ICA
IPC, Index (complementary) Version 1-7 (7)	/ICI	S (C12P019-40(L)C12R001:465)/ICI	ICI
IPC, Main, Version 1-7 (7)	/ICM	S C23C001-08/ICM	ICM
Indexing Codes (EPO)	/ICO	S K61M/ICO	ICO
IPC, Secondary (7)	/ICS	S C12P019-40/ICS	ICS
Indeling der Techniek (EPO/NL)	/IDT	S 12C2P2E4/IDT	IDT
Inventor	/IN (or /AU)	S NICKOLA RICHARD?/IN	IN
Inventor Address	/INA	S HEIDELBERG/INA	INA

INPADOCDB

Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Inventor Address, Country (WIPO code and text)	/IN.CNY	S GB/IN.CNY	INS
Inventor INPADOC Standard	/INS	S AGARWAL S?/INS	INS
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	/IPC	S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	IC, ICA, ICI, ICM, ICS, IPCI, IPCR
IPC, Action Date	/IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Keyword Terms	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Version from IPC	/IPC.VER	S 200601/IPC.VER	IPC.TAB
Language (ISO code and text)	/LA	S DE/LA	LA
Language of Filing (ISO code and text)	/LAF	S FR/LAF	LAF
National Patent Classification	/NCL	S U1S1002/NCL	NCL
Patent Assignee (8)	/PA (or /CS)	S INLAND STEEL/PA S BROWN WILLIAMSON/CS	PA
Patent Assignee Address	/PAA	S US/PAA AND EASTMAN KODAK/PAS	PAA
Patent Assignee, Country	/PA.CNY	S GB/PA.CNY	PAS
Patent Assignee INPADOC Standard	/PAS	S INLAND STEEL CO?/PAS S (BROWN(S)TOBACCO)/PAS	PAS
Patent Assignee Standard, Cited	/PAS.D	S TOSHIBA CORP/PAS.D	REP
Patent Country (WIPO code and text)	/PC	S DE/PC AND IBM/PAS AND 1988/PY	PI
Publication Date (2)	/PD	S 19990104/PD	PI
Patent Information Publication Type	/PIT	S ARA1/PIT	PIT
Patent Kind Code	/PK	S ZWA1/PK	PI
Patent Number (3)	/PN	S FI990202U/PN	PI
Priority Kind Text	/PRAIT	S ARA PATENT APPLICATION/PRAIT	
Priority Country (WIPO code and text)	/PRC	S JP/PRC AND 19880101/PRD	PRAI
Filing Country for PCT Priorities (WIPO code and text)	/PRC.WO	S DE/PRC.WO	PRAI
Priority Date (2)	/PRD	S JP/PRC AND 19880101-19880331/PRD	PRAI
Priority Kind Code	/PRK	S DEA/PRK	
Priority Number (3)	/PRN	S US1990-184420/PRN	PRAI
Priority Year (2)	/PRY	S 1998/PRY AND US/PRC	PRAI
Priority Year, First (2)	/PRYF	S GB/PC AND 1998/ PRYF	PRAI
Publication Year (2)	/PY	S 1999/PY	PI
Referenced Non-Patent Literature	/REN	S MAYER/REN	REN
Non-Patent Literature XP- Document Number	/REXP	S XP002235691/REXP	REXP
Referenced Patent Number	/RPN	S EP1234567/RPN	REP
Origin of Citation	/SRT	S EXA/SRT	REN, REP REXP
Patent Status	/STA	S GRANTED/STA AND LASER/TI	STA
Title	/TI	S (APPARAT? (S) SMOKE (S) FILTER#)/T	TI
Title Language (ISO code and text)	/TL	S EN/TL S ENGLISH/TL	TL
Update Date (2)	/UP	S L1 AND UP>20070102	UP
Update Date for combined or split Patent Family (9)	/UPFC	S UPFC=OCT 2009	UPALL
Update Date of the BIB fields (2)	/UPBB	S L1 AND UPBB>20070222	UPALL
Update Date Classifications (2)	/UPCC	S L1 AND UPCC>20070222	UPALL
Update Date Patent Family (2) (All Updates)	/UPFA	S 20070329/UPFA	UPALL
Update Date Patent Family Bibliographic (2)	/UPFB	S 20070215/UPFB AND L7	UPALL
Update Date Patent Family Bibliographic (2)	/UPFD	S 20070215/UPFD	UPALL

Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Update Date New Publication and/or Legal Status Changes (2)	/UPFE	S 20070321/UPFE	UPALL
Update Date Patent Family Legal Status (2)	/UPFL	S 20070321/UPFL	UPALL
Update Date Patent Family Publication Level (2)	/UPFP	S 20070222/UPFP	UPALL
Update Date Legal Status (2)	/UPLS	S UPLS=20070222	LS, LSUP
Update Date All Patent Changes (2)	/UPM	S L1 AND 20070222/UPM	not displayed
Update Week (INPADOC Week) (2)	/UW	S UW=200641 AND L3	UW

- (1) This field is available for selected countries and patent publications.
 (2) Numeric search field that may be searched using numeric operators or ranges.
 (3) Either STN or Derwent format may be used.
 (4) For German Utility Models: Advertisement of registration.
 (5) Available since 2006.
 (6) Available since week 200639
 (7) Search in IPC8 format also available.
 (8) Search with implied (S) proximity is available.
 (9) Available since September 2009.

Legal Status Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Entry Date New Publication and/or New Legal Status (1)	/EDLS	S EDLS=FEB 2009	not displayed
Entry Week Legal Status	/EWLS	S 200641-200642/EWLS	LS2
Legal Status Basic Index (contains legal status agent (LSG), legal status free format text (LSFT), legal status inventor (LSIN), legal status patent opponent (LSOP), and legal status patent assignee (LSPA) fields)	/LSBI	S LASER?/LSBI S ANACOMP/LSBI S OPPOSITE/LSBI	LS
Legal Status Code (code and text)	/LSC	S EP111L/LSC	LS
Legal Status Code Category	/LSC2	S LIC/LSC2	LS
Legal Status Code Country (WIPO code and text)	/LSCC	S BE/LSCC	LS
Legal Status Code Text	/LSTX	S CORRECTION/LSTX	LS
Legal Status Country (WIPO code and text)	/LSCY	S UNITED KINGDOM/LSCY	LS
Legal Status Date in Force Country (1)	/LSDF	S LSDF=20050109	LS
Legal Status Date INPADOC GAZETTE (1)	/LSD	S LSD=JAN 2002	LS
Legal Status Designated States (WIPO code and text)	/LSDS	S AU/LSDS S AUSTRALIA/LSDS	LS
Legal Status Free Format Text	/LSFT	S TELECOMMUNICATION/LSFT	LS
Legal Status Indicator	/LSCI	S POSITIVE/LSCI AND L3	LS
Legal Status IPC	/LSIC	S 41J320/0/LSIC	LS
Legal Status Patent Assignee	/LSPA	S (MAN(S)CERAMICS)/LSPA	LS
Legal Status Patent Inventor	/LSIN	S MAYER, BERND/LSIN S (MAYER(S)BERND)/LSIN	LS

INPADOCDB

Legal Status Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Legal Status Patent Opponent	/LSOP	S SIEMENS AG/LSOP	LS
Legal Status Payment Year (1)	/LSPMY	S 18/LSPMY	LS
Legal Status Publication Country (WIPO code and text)	/LSPC	S CA/LSPC S CANADA/LSPC	LS
Legal Status Publication Date (1)	/LSPD	S LSPD=JAN 1998	LS
Legal Status Publication Kind Code	/LSPK	S ES00/LSPK	LS
Legal Status Publication Number	/LSPN	S EP200212/LSPN	LS
Legal Status Publication Year (1)	/LSPY	S 1999-2000/LSPY	LS
Legal Status Represent./Agent	/LSAG	S (LORENZ AND PHILIPPS)/LSAG	LS
Legal Status SPC Number	/LSSPC	S EU/1/00/129/001/LSSPC	LS
Legal Status SPC, Expiry Date (1)	/LSSPC.XD	S LSSPC.XD>2005	LS
Legal Status SPC, Extension Date (1)	/LSSPC.EX	S 20010910/LSSPC.EX	LS
Legal Status SPC, Filing Date (1)	/LSSPC.FD	S 19950101-19961231/LSSPC.FD	LS
Update Legal Status (1)	/UPLS	S 20070208/UPLS	LS, LSUP

(1) Numeric search field that may be searched using numeric operators or ranges.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (1)	/APPS	/AP,/PRN	S DE1984-3400052/APPS S 1984DE-3400052/APPS	AI, PRAI
Inventor Group	/INSS	/IN, /INS, /LSIN	S MEIER/INSS	IPC
Patent Assignee Group	/PASS	/PA, /PAS, /LSPA	S MEIER/PASS	PI
Patent Countries	/PCS	/PC,/DS	S BE/PCS	PI, DS
Patent Number Group (1)	/PATS	/PN, /RPN	S WO1989004114/PATS	PI, REP

(1) Either STN format or Derwent format may be used.

IPC THESAURUS

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

IPC THESAURUS (cont'd)

Code	Content	Examples
ADVANCED (ADV) ALL BRO (MAN) BT BTn	Advanced Level Codes for the Core Level IPC Code All Associated Terms (BT, SELF, NT, RT) Complete Class Broader Term (SELF, BT) Broader Term (SELF, BT) up to the next n levels (n =1,2,...)	E A61K0066-02+ADVANCED/IPC E C01C003-00+ALL/IPC E C01C+BRO/IPC E C01F001-00+BT/IPC E C01F001-21+BT2/IPC
CORE (COR) ED HIE	Core Codes for the Advanced Level IPC Code Complete title of the SELF term and IPC manual Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E G08C0019-22+CORE/IPC E C01F001-00+ED/IPC E C011003-00+HIE/IPC
INDEX KT NEXT NT NTn	Complete title of the SELF term Keyword Term (catchwords) (SELF, KT) Next Classification Narrower Terms (SELF, NT) Narrower Terms (SELF, NT) down to the next n levels (n =1,2,...)	E C01F001-00+INDEX/IPC E CYANOGEN+KT/IPC E C01C001-00+NEXT5/IPC E C01C+NT/IPC E C01C+NT3/IPC
PREVn RT (SIB) TI	Previous Classification (n =1,2,...) Related Terms (SELF, RT) Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01C001-12+PREV10/IPC E C01C003-20+RT/IPC E C01F001-00+TI/IPC

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PI. The fields are displayed or printed in the order requested.

You can combine all display fields and all display formats with the qualifier .M to display the content for all publications of a record.

You can combine all display fields and all display formats with the qualifier .F to display the content for all family members (will be charged as a family display).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract in English	D AB
ABDE	Abstract in German	D ABDE
ABES	Abstract in Spanish	D ABES
ABEQ (1)	Display of an English equivalent abstract	D ABS
ABFR	Abstract in French	D ABFR
ABOL	Abstract in Other Language	D ABOL
AI (2)	Application Information	D AI
AIT	Application Kind Code Text	D AIT
AN	Accession Number	D AN
CHG	Changes (Indicator for changes in the last update)	D CHG
DAV	Data Availability	D DAV
DF	Date of Force	D DF
DS	Designated States	D DS
DT (TC)	Document Type	D DT
ED	Entry Date	D ED
EDP	Entry Date Patent	D EDP

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
EPC (ECLA)	European Patent Classifications (EPC, ICO, IDT)	D EPC
EW	Entry Week	D EW
FA	Field Availability	D FA
FDT (PT)	Filing Details	D FDT
FN	Family Number	D FN
IC	International Patent Classification (ICM, ICS)	D IC
ICA	IPC, Additional (supplementary)	D ICA
ICI	IPC, Index (complementary)	D ICI
ICM	IPC, Main	D ICM
ICS	IPC, Secondary	D ICS
IN	Inventor	D IN
INA (IN.CNY)	Inventor Address	D INA
INS	Inventor INPADOC Standard	D INS
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
NCL	National Patent Classification	D NCL
PA (CS)	Patent Assignee	D PA
PAA	Patent Assignee Address	D PAA
PAS	Patent Assignee INPADOC Standard	D PAS
PI (PN) (2)	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PRAI (PRN) (2)	Priority Information	D PRAI
PRAIT	Priority Kind Text	D PRAIT
REC (RE.CNT)	Reference Count	D REC
REN (NPL)	Referenced Non-Patent Literature	D REN
REP	Referenced Patents	D REP
REXP	Non-Patent Literature XP-Document Number	D REXP
STA	Status	D STA
TI	Title	D TI
TL	Title Language	D TL
UP	Update Date	D UP
UW	Update Week (INPADOC Week)	D UW
ABS (1)	AN, AB, ABDE, ABES, ABFR, ABOL, ABEQ	D ABS
ALL (2)	BIB, all Abstracts, IND, FA, CHG	D ALL
ALLO (2)	ALL, for previous update	D ALLO
IALL (2)	ALL, indented with text labels	D IALL
BIB (2)	AN, ED, EW, UP, UW, FN, UPFC, TI, TL, IN, INS, INA, PA, PAS, PAA, DT, LA, LAF, PI, PIT, DAV, STA, DF, DS, XS, AI, AIT, PRAI, PRAIT, REC (The default format is BIB.M)	D BIB
IBIB (2)	BIB, indented with text labels	D IBIB
APPS (2)	Application Number Group (AI, PRAI)	D APPS
IND	AN, ED, EW, UP, UW, IPC, EPC, ICO, IDT, NCL	D IND
IPC	ICM, ICS, ICA, ICI, IPCR, IPCI	D IPC
IPC.TAB	IPC, IPC.KW, IPC.ACD, IPC.VER, in tabular display	D IPC.TAB
LS	AN, UPLS, Legal Status	D LS
LS2	Legal Status, detailed version with display headers	D LS2
LSUP	Last LS Update	D LSUP
MAX (2)	ALL.M plus all Abstracts, PRAIT, RLI, AIT, FDT, LS, SFN	D MAX
IMAX (2)	MAX, indented with text labels	D IMAX
MAXO (2)	MAX, with original data in UTF-8 characters	D MAXO
MAXO2 (2)	MAXO, plus display of special characters in the abstract	D MAXO2

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
PATS (2) RE SCAN (3) STD (2) TRIAL (TRI, FREE, SAMPLE, SAM)	Patent Number Group (PI, REP) Cited References (REP, REXP, REN) TI latest publication (random display without answer number) BIB, IND TI, FA	D PATS D RE D SCAN D STD D TRIAL
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

- (1) ABEQ only for records entered or updated after week 200740.
- (2) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.
- (3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

FAMILY DISPLAY and PRINT Formats

Format	Content	Examples
TIPI.F PILS.F (1) BIBLS (1) CFAM (1) CFAM2 (1) DFAM (1,2) EFAM (1) FAM (1) FAMLS (1) FAM2 (1) FFAM (1) FFAM.PC (1,3) IFAM (1) LFAM (1) MFAM (1) SFAM (1) UPALL	TI + LS for all patent family members PI + LS for all patent family members BIB + LS for all patent family members Condensed FAM with only PI in the table Display for the condensed family table PI, AI, PRAI FAM, delimited for post processing FAM, but the priority information constitutes the header AN, table of patent family information Comprises the family table CFAM2 plus a list of all legal status entries, sorted by legal status date LSD AN, table of Patent Family information, another order STD + LS for each member of the family FFAM for a specified country only Combines indented FAM and IMAX.F AN, PI, LSUP for all members of a patent family MAX for each family member Display of the EPO 'simple patent family' (SFN) within the INPADOC patent family table Table of update dates (AN, FN, UPFC, UPBB, UPCC, ED, EDP, UPFB, UPFP, UPFD, EDF, UPFL)	D TIPI.F D PILS.F D BIBLS D CFAM D CFAM2 D DFAM D EFAM D FAM D FAMLS D FAM2 D FFAM D FFAM.PC D IFAM D LFAM D MFAM D SFAM D UPALL

- (1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.
- (2) SET LINE 100 is recommended.
- (3) PC = AT BE CA CH CN DE DK EP ES FI FR GB JP KR NO RU SE US WO

FAMILY DISPLAY and PRINT Formats – Weekly SDI

Format	Content	Examples
FFAMED (1) FFAMED.PC (1,2) FFAMUP (1) FFAMUP.PC (1,2) IFAMED (1) IFAMUP (1) LFAMUP (1) LFAMUP.PC (1,2)	STD for new publications and/or LSUP for each updated family FFAMED for a specific country only STD + LS for each updated family FFAMUP for a specific country only Indented FFAMED plus patent family table Indented FFAMUP plus patent family table AN, PI, LSUP for all updated members of a patent family LFAMUP for a specific country only	D FFAMED D FFAMED.PC D FFAMUP D FFAMUP.PC D IFAMED D IFAMUP D LFAMUP D LFAMUP.PC

(1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

(2) PC = AT BE CA CH CN DE DK EP ES FI FR GB JP KR NO RU SE US WO

FAMILY DISPLAY and PRINT Formats – Monthly SDI

Format	Content	Examples
FFAMED4 (1) FFAMUP4 (1) IFAMED4 (1) IFAMUP4 (1) LFAMUP4 (1)	STD for new publications and/or LSUP for each updated family STD + LS for each updated family Indented FFAMED4 plus patent family table Indented FFAMUP4 plus patent family table AN, PI, LSUP for all updated members of a patent family	D FFAMED4 D FFAMUP4 D IFAMED4 D IFAMUP4 D LFAMUP4

(1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

Sorting within the PATENT FAMILY DISPLAY Formats

Format	Content
FAM DFAM EFAM FFAM LFAM CFAM	PRN (Priority Number) PRN (Priority Number) PRN (Priority Number) PN (Patent Number) of the highest level PN (Patent Number) of the highest level AP (Application Number)

Sorting within the PATENT FAMILY DISPLAY Formats

You can define the sort parameter in family display formats. Depending on the formats used, options are priority date (.PRD), publication date (.PD), patent number (.AP), application date (.AD). The following combinations are available.

Format	Content
FAM.PRD CFAM.PD DFAM.PRD DFAM.AP DFAM.AD DFAM.PN DFAM.PD EFAM.PRD	Priority Date Publication Date Priority Date Application Number Application Date Patent Number Patent/Publication Date Priority Date

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract in English	AB	Y	Y
Abstract in German	ABDE	Y (2)	Y
Abstract in Spanish	ABES	Y (2)	Y
Abstract in French	ABFR	Y (2)	Y
Abstract in Other Language	ABOL	Y (2)	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Kind Code Text	AIT	Y	Y
Application Kind Code	AK	Y	Y
Application Number	AP (AI)	Y (3)	Y
Application Number Group	APPS	Y (3,4)	N
Application Year	AY	Y	Y
Changes (Indicator for the changes in the last update)	CHG	Y	N
Date of Force	DF	Y	Y
Designated State	DS	Y	N
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	N
Entry Date Patent	EDP	Y	N
European Patent Classification	EPC (ECLA)	Y	Y
Entry Week	EW	Y	N
International Patent Classification	IC	Y	N
IPC, Additional (supplementary)	ICA	Y	Y
IPC, Index (complementary)	ICI	Y	Y
IPC, Main	ICM	Y	Y
IPC, Secondary	ICS	Y	Y
Indexing Codes (EPO)	ICO	Y	Y
Indeling der Techniek (EPO/NL)	IDT	Y	Y
Inventor	IN (AU)	Y	Y
Inventor Address, Country	IN.CNY	Y	Y
Inventor Address	INA	Y	Y
Inventor INPADOC Standard	INS	Y	Y
International Patent Classification	IPC	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (5)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (5)	N
IPC, Core Level Symbols	IPC.C	Y (5)	N
IPC, Core Level Symbols for Invention	IPC.CI	Y (5)	N
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 to the present	IPC.F	Y (5)	Y
IPC, Initial	IPCI	Y (5)	N
IPC, Reclassified	IPCR	Y (5)	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Legal Status Representative/Agent	LSAG	Y	N
Legal Status Code	LSC	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Legal Status Code Category	LSC2	Y	N
Legal Status Code Country	LSCC	Y	N
Legal Status Date INPADOC GAZETTE	LSD	Y	N
Legal Status Free Format Text	LSFT	Y	N
Legal Status IPC	LSIC	Y	N
Legal Status Patent Inventor	LSIN	Y	N
Legal Status Patent Opponent	LSOP	Y	N
Legal Status Patent Assignee	LSPA	Y	N
Legal Status Publication Country	LSPC	Y	N
Legal Status Publication Date	LSPD	Y	N
Legal Status Payment Year	LSPMY	Y	N
Legal Status Publication Number	LSPN	Y	N
Legal Status SPC Number	LSSPC	Y	N
Legal Status SPC, Extension Date	LSSPC.EX	Y	N
Legal Status SPC, Filing Date	LSSPC.FD	Y	N
Legal Status SPC, Expiry Date	LSSPC.XD	Y	N
National Patent Classification	NCL	Y	Y
Occurrence Count of Hit Terms	OCC	N	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Assignee Address	PAA	Y	Y
Patent Assignee INPADOC Standard	PAS	Y	Y
Patent Assignee Standard, Cited	PAS.D	Y	N
Patent Number Group	PATS	Y (3,6)	Y
Patent Country	PC	Y	Y
Publication Date	PD	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN (PI)	Y (3)	Y
Priority Kind Text	PRAIT	Y	Y
Priority Country	PRC	Y	Y
Priority Country, First	PRCF	Y	Y
Priority Country, First of PCT Priorities	PRCF.WO	Y	Y
Priority Date	PRD	Y	Y
Priority Kind Code	PRK	Y	Y
Priority Number	PRN (PRAI)	Y (3)	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y (7)	Y
Publication Year	PY	Y	Y
Referenced Patents	REP	Y	Y
Referenced Non-Patent Literature	REXP	Y	Y
Title	TI	Y (default)	Y
Update Date	UP	Y	N
Update Week	UW	Y	N

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /AB to the terms created by SELECT.
- (3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- (4) Selects or analyzes AP, PRN, and appends /APPS to the terms created by SELECT.
- (5) Appends /IPC to the terms created by SELECT.
- (6) Selects or analyzes /PN, /RPN with /PATS appended to the terms created by SELECT.
- (7) SELECT or ANALYZE HIT are not valid with this field.

Update Codes (for SDI also)**Update codes or entry dates associated with records**

Field Name	Search Code	Search Examples	Display Codes
Entry Date	/ED	S L1 AND ED>DEC 2006	ED
Entry Date + Legal Status Update	/EDLS	S EDLS = JAN 2008	not displayed
Entry Date Patent	/EDP	S 20061026/EDP	EDP, UPALL
Entry Date Priority	/EDPR	S 29 JAN 2009/EDPR	PRAI
Update Date	/UP	S 20070102/UP	LS
Update Legal Status	/UPLS	S 20070222/UPLS	LS
All updates of a record	/UPM	S 20070215/UPM	not displayed

Update codes or entry dates associated with patent families (1,2)

Field Name	Search Code	Search Examples	Display Codes
Entry Date new patent family	/EDF	S L1 AND EDF>21 MAR 2007	UPALL
All changes in a patent family	/UPFA	S L1 AND 20070329/UPFA	not displayed
Any change of a bibliographic element in a patent family	/UPFB	S L1 AND 20070215/UPFB	UPALL
Update Date for combined or split Patent Family (3)	/UPFC	S L1 AND UPFC=OCT 2009	UPFC
Entry of a new database record (document) into a patent family (level 1)	/UPFD	S L1 AND 20070215/UPFD	UPALL
Entry of a new publication and changes in legal status	/UPFE	S L1 AND 20070321/UPFE	not displayed
Any change of a legal status in a patent family	/UPFL	S L1 AND 20070321/UPFL	UPALL
Entry of a new publication level into a patent family	/UPFP	S L1 AND 20070222/UPFP	UPALL

(1) Available since February 2007.

(2) Special display formats available for monitoring patent families weekly.

(3) Available since September 2009.

Sample Records**DISPLAY MAX**

AN 24180089 INPADOCDB UP 20061123
 FN 13550763
 TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
 Coated sheet cutting method and apparatus.
 Procède et appareil pour la coupe d'une feuille revetue.
 TL German; English; French
 IN KAWAI, HIROKAZU
 INS KAWAI HIROKAZU, JP
 PA FUJI PHOTO FILM CO., LTD.
 PAS FUJI PHOTO FILM CO LTD, JP
 DT Patent
 PI EP 1488896 A1 20041222 English
 PIT EP A1 APPLICATION PUBLISHED WITH SEARCH REPORT
 DAV 20041222 examined-printed-without-grant
 STA PRE-GRANT PUBLICATION

INPADOCDB

DS R: DE FR GB
 AI EP 2004-13971 A 20040615
 AIT EPA Patent application
 PRAI JP 2003-174783 A 20030619 (JPA)
 JP 2003-174784 A 20030619 (JPA)
 PRAIT JPA Patent application
 REP JP 2001138285 A (SEA, npl, Cat: Y)
 JP 06168444 A (SEA, npl, Cat: Y)
 REXP XP000510813 (SEA, Cat: A)
 REN (1) PATENT ABSTRACTS OF JAPAN vol. 2000, no. 22, 9 March 2001
 (2001-03-09) & JP 2001 138285 A (SONY CORP), 22 May 2001 (2001-05-22)
 (SEA, Cat: Y)
 (2) PATENT ABSTRACTS OF JAPAN vol. 0185, no. 05 (P-1803), 21 September
 1994 (1994-09-21) & JP 6 168444 A (MATSUSHITA ELECTRIC IND CO LTD), 14
 June 1994 (1994-06-14) (SEA, Cat: Y)
 (3) KLEIN H: "LANGSSCHNEIDEN VON BAHNFORMIGEN MATERIALIEN DER
 KREISMESSER-SCHERENSCHNITT UND SEINE OPTIMALE EINSTELLUNG FUR DAS
 LANGSSCHNEIDEN BAHNFORMIGER MATERIALIEN (TEIL 3)" COATING, VERLAG COATING
 THOMAS & CO, CH, vol. 28, no. 5, 1 May 1995 (1995-05-01), pages 176-179,
 XP000510813 ISSN: 0590-8450 (SEA, Cat: A)

IC.V 7
 ICM B26D001-24
 IPCR B26D0001-24 [I,A]; B26D0007-26 [N,A]
 B26D0001-01 [I,C*]; B26D0007-26 [N,C*]
 EPC B26D0001-24B
 ICO L26D0007:26C2
 AB A discoid lower blade and a discoid upper blade, having a sharper knife
 angle compared with that of the lower blade, are arranged such that
 rotational axes thereof are parallel to each other, and portions of the
 blades overlap one another in the direction that the rotational axes
 extend. A sheet with a coating layer on one side is fed through and
 shear-cut between the upper and lower blades in the direction
 perpendicular to the rotational axes, with the surface of the sheet
 opposite the coating layer in contact with a periphery of the lower blade
 while the blades are rotated. When the sheet is shear-cut, a contact
 start position, where contact between the sheet and the upper blade
 starts, is positioned upstream in the feed direction of the sheet but
 outside a contacting area of the sheet, where the sheet contacts the
 periphery of the lower cutting blade. Alternatively, the contact start
 position starts within the contacting area and an overlap between a part
 of the upper cutting blade and a part of the lower cutting blade is
 maintained less than 1.5 mm. <IMAGE>.

AL English
 AS EPO
 FA AB; AI; AN; DAV; DS; DT; EPC; ICM; ICO; IN; INS; IPC; IPCR; LA; PA; PAS;
 PI; PIT; PRAI; REN; REP; REXP; TI
 AN 24180089 INPADOCDB UP 20061005
 TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
 Coated sheet cutting method and apparatus.
 Procédé et appareil pour la coupe d'une feuille revêtue.

TL German; English; French
 IN KAWAI, HIROKAZU
 INS KAWAI HIROKAZU, JP
 PA FUJI PHOTO FILM CO., LTD.
 PAS FUJI PHOTO FILM CO LTD, JP

DT Patent
 PI EP 1488896 B1 20061004 English
 PIT EPB1 PATENT SPECIFICATION
 DAV 20061004 printed-with-grant
 STA GRANTED
 DS R: DE FR GB
 AI EP 2004-13971 A 20040615
 AIT EPA Patent application
 PRAI JP 2003-174783 A 20030619 (JPA)
 JP 2003-174784 A 20030619 (JPA)
 PRAIT JPA Patent application
 IPCI B26D0001-24 [I,A]; B26D0001-01 [I,C*]
 IPCR B26D0007-26 [N,A]
 B26D0007-26 [N,C*]
 EPC B26D0001-24B
 ICO L26D0007:26C2
 FA AI; AN; DAV; DS; DT; EPC; ICO; IN; INS; IPC; IPCI; IPCR; LA; PA; PAS; PI;
 PIT; PRAI; TI

LEGAL STATUS

AN 24180089 INPADOCDB
 20041222 EPAK + DESIGNATED CONTRACTING STATES:
 EP A1
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LI LU
 MC NL PL PT RO SE SI SK TR
 20041222 EPAX + EXTENSION OF THE EUROPEAN PATENT TO
 AL HR LT LV MK
 20050803 EP17P + REQUEST FOR EXAMINATION FILED
 20050603
 EXA Examination, Search Report
 20050914 EPAKX + PAYMENT OF DESIGNATION FEES
 DE FR GB
 20061004 EPAK + DESIGNATED CONTRACTING STATES:
 EP B1
 DE FR GB
 20061004 EPREG REFERENCE TO A NATIONAL CODE
 GBFG4D + GB: EUROPEAN PATENT GRANTED
 200641
 20061116 EPREF CORRESPONDS TO:
 DE 602004002620 P 20061116
 200646
 20070314 EPRAP2 PATENT OWNER REASSIGNMENT (CORRECTION)
 FUJIFILM CORPORATION
 CHG Change of Owner, Inventor, Applicant
 200711.....20070315
 20070411 EPREG REFERENCE TO A NATIONAL CODE
 GB732E GB: PROCEEDING UNDER SECTION 32 PATENTS ACT 1977
 CHG Change of Owner, Inventor, Applicant
 200716.....20070419
 20070420 EPET + FR: TRANSLATION FILED
 200719.....20070510

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INPADOCDB**DISPLAY FAM**

PATENT FAMILY INFORMATION

AN 24180089 INPADOCDB

+-----PRAI-----+			+-----AI-----+		
JP	2003-174783	A 20030619	CN	2004-10059710	A 20040617
			DE	2004-602004002620	T 20040615
			EP	2004-13971	A 20040615
			JP	2003-174783	A 20030619
			US	2004-868808	A 20040617
JP	2003-174784	A 20030619	CN	2004-10059710	A 20040617
			DE	2004-602004002620	T 20040615
			EP	2004-13971	A 20040615
			JP	2003-174784	A 20030619
			US	2004-868808	A 20040617
+-----AI-----+			+-----PI-----+		
CN	2004-10059710	A 20040617	CN	1572446	A 20050202
DE	2004-602004002620	T 20040615	DE	602004002620	D1 20061116
EP	2004-13971	A 20040615	EP	1488896	A1 20041222
			EP	1488896	B1 20061004
JP	2003-174783	A 20030619	JP	2005007524	A 20050113
JP	2003-174784	A 20030619	JP	2005007525	A 20050113
US	2004-868808	A 20040617	US	20040255743	A1 20041223

2 priorities, 6 applications, 7 publications

DISPLAY ALL

AN 51399732 INPADOCDB UP 20070426 UW 200717

FN 34407383

TI Neck fastening for mechanical line-fastening of insulating material and sealing tracks on flat roofs consists of rail with holes and fastenings formed from screws anchored onto rail bottom and supported with head on rail.

Kehlbefestigung fuer die mechanische Linienbefestigung von Daemmmaterialien und Abdichtungsbahnen auf Flachdaechern.

TL English; German

PA HARALD ZAHN GMBH

PAS ZAHN HARALD GMBH, DE

DT Patent

PI DE 102005022624 A1 20061123

PIT DEAI DOC. LAID OPEN (FIRST PUBLICATION)

DAV 20061123 unexamined-printed-without-grant

STA PRE-GRANT PUBLICATION

AI DE 2005-102005022624 A 20050517

AIT DEA Patent application

PRAI DE 2005-102005022624 A 20050517 (DEA)

PRAIT DEA Patent application

IPCI E04D0005-14 [I,A]; E04B0001-74 [I,A]; E04D0003-36 [I,A]; E04D0005-00 [I,C*]; E04B0001-74 [I,C*]; E04D0003-36 [I,C*]

AB Neck fastening consists of a rail with holes made in the rail bottom and individual fastenings. Fastenings are each formed from a screw (1) which is put in the rail base, supported with its head (3) on the rail and which cuts with its end into the roof bottom or juts into a wall plug anchored into the roof base. From both sides of the hole on the rail narrow positioning edges or noses protrude on which the underside of the screw head lies. When its clamping force is held steady suspended see-saw like between its positioning edges or noses, the rail lies on the underside of the screw head.

AL English
AS transcript
FA AB; AI; AN; DAV; DT; IPC; IPCI; PA; PAS; PI; PIT; PRAI; TI
CHG TI A

DISPLAY BIB RE

AN 59518659 INPADOCDB ED 20091015 EW 200942 UP 20091022 UW 200943
FN 38441986
TI Verfahren zur Beschichtung eines metallischen Substrats mit einer Schicht
aus niedrig legiertem Stahl.
Method to coat a metallic substrate with low alloy steel layer.
Procede de revetement d'un substrat metallique avec un revetement a
faible alliage d'acier.
TL German; English; French
IN CHILDS, CHRISTOPHER; MARCHANT, GEOFFREY
INS CHILDS CHRISTOPHER, GB; MARCHANT GEOFFREY, GB
PA SIEMENS AKTIENGESELLSCHAFT
PAS SIEMENS AG, DE
DT Patent
PI EP-----2108476 A1 20091014 English
PIT EPA1 APPLICATION PUBLISHED WITH SEARCH REPORT
DAV 20091014 examined-printed-without-grant
STA PRE-GRANT PUBLICATION
DS R: AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI
LT LU LV MC MT NL NO PL PT RO SE SI SK TR
XS R: AL BA MK RS
AI 2008EP-000007060 A 20080409
AIT EPA Patent application
PRAI 2008EP-000007060 A 20080409 (EPA, 20091015, Y)
PRAIT EPA Patent application
REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR
THIS RECORD. ALL CITATIONS ARE AVAILABLE IN THE RE FORMAT.
REP EP 1835189 A2 (SEA, pat, Cat: X) GEN ELECTRIC, US
EP 1898048 A1 (SEA, pat, Cat: A) HITACHI LTD, JP
WO 2006111520 A1 (SEA, pat, Cat: A) SIEMENS AG, DE; SHEPHERD
ANDREW, GB; WALKER PAUL
METHEW, GB
US 4300474 A (SEA, pat, Cat: AD) ROLLS ROYCE
GB 2052566 A (APP, pat) ROLLS ROYCE
REXP XP008053341 (SEA, Cat: Y)
REN (1) NOWOTNY S: "BESCHICHTEN, REPARIEREN UND GENERIEREN DURCH
PRAEZISIONS-AUFTRAGSCHWEISSEN MIT LASERSTRAHLEN//CLADDING, REPAIR, AND
FREEFORMING BY BUILD-UP WELDING USING LASER IRRADIATION" VAKUUM IN
FORSCHUNG UND PRAXIS, WILEY-VCH, WEINHEIM, DE, vol. 14, no. 1, 1 February
2002 (2002-02-01), pages 33-37, XP008053341 ISSN: 0947-076X (SEA, Cat: Y)
REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR
THIS RECORD.

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.

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E-mail: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
E-mail: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.de

In Japan

JAICI (Japan Association for
International Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
E-mail: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp